What is claimed is:

1. A scatter correction device that applied to tomographic scanners, said scatter correction device comprising at least one beam stopper, and at least one steady support component, each beam stopper having two ends fixed on said support component, during scanning an object, said scatter correction device being placed as close to the object as possible to cover said object.
2. The scatter correction device of claim 1, wherein said device does not cover the bottom of the object when it is applied to a positron emission tomography scanner.
3. The scatter correction device of claim 1, wherein said beam stoppers are made of high Z materials.
4. The scatter correction device of claim 1, wherein said support components are made of the material that radiation passes through without causing any affections.
5. The scatter correction device of claim 1, wherein said scatter correction device has a vary appearance for the objects that are to be scanned and have different shapes and sizes.
6. The scatter correction device of claim 2, wherein said high Z materials includes lead and wolfram.
7. The scatter correction device of claim 2, wherein each beam stoppers is a thin stick having a thickness from the range 2 mm to 5 mm.
8. The scatter correction device of claim 3, wherein said material is plastic.
9. A method of correcting scatter for tomographic scanners with a scatter

correction device including at least one beam stopper and at least one steady support component, said method comprising the steps of:

(a) scanning an object with and without beam stopper to generate a first two counts , and using two air scans to generate a second two counts for the air scans;

(b) processing said first and second two counts and computing a scattered radiation at the beam stopper's location;

(c) recovering said scattered radiation for a whole scattered sinogram, wherein a sinogram is referred to a file that stores the projection data of a scanner;

(d) yielding only primary sinogram by subtracting said scattered radiation from original data; and

(e) reconstructing the image of a source object and obtaining a scatter corrected image.

10. The method of claim 8, wherein said step (c) is implemented by an approximation approach.

11. The method of claim 8, wherein said step (c) is implemented by an interpolation method.

12. The method of claim 8, wherein said step (c) is implemented by a dual-energy window method.